

<b>Notice of References Cited</b>	Application/Control No. 10/565,107		Applicant(s)/Patent Under Reexamination JEONG ET AL.	
	Examiner Keath T. Chen		Art Unit 1792	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2001/0028074	10-2001	Kutsunai et al.	257/295
*	C	US-5,135,608	08-1992	Okutani, Ken	438/584
*	D	US-6,136,725	10-2000	Loan et al.	438/758
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	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 06-254416	09-1994	Japan	Takada	B01L 1/00
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#### NON-PATENT DOCUMENTS

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	U	English abstract of JP 06-254416, Takada, 09-1994
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.